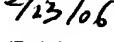
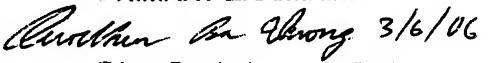


Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/053,202		BAN ET AL.	
	Examiner		Art Unit	
	Yuwen Pan		2682	

ORIGINAL			CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
455	556.1	455	556.2	67.11	452.1	452.2		
INTERNATIONAL CLASSIFICATION								
H 04 B	17100							
H 04 Q	7120							
H 04 M	1100							
	/							
	/							
  Assistant Examiner) (Date)			QUOCHIEN B. VUONG PRIMARY EXAMINER   (Primary Examiner) (Date)			Total Claims Allowed: 19		
  (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1			O.G. Print Fig. 3B&3C		

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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